

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
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			Examiner	Art Unit	Page 1 of 1
			Christopher M. Keehan	1712	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,228,480 B1	05-2001	Kimura et al.	428/328
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 0633064 A1	01-1995	JP	Murasawa et al.	
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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